

SEARCHED

Class	Sub.	Date	Exmr.
705	40 39 42 34+57+52	1/22/02	JEC
709	229 238 241 244 221 219 220	1/18/02	JEC
705	14	6/2-4/04	JEC
1			

INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	Date	Exmr.
① EIC Plus Word Search of Specifications	4/22-1/18/02	JEC
② NPL Search by EIC using search designed by Examiner		
③ Examiner's Search of 147 Patent References obtained from EIC Search.		
④ Examiner's review of Abstracts of applicant's Information Disclosures (Japanese & U.S. Patents and some non-patent literature)		
Searches primary reference and the two secondary references	4/22-1/18/03	JEC
Please See EIC Search History	6/2-4/04	JEC
INVENTOR NAME SEARCH	10/02/02	JEC

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